

**Search Notes**

Application/Control No.

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Examiner

VAN T. PHAM

Applicant(s)/Patent under  
Reexamination

TANAKA, AKIHIRO

Art Unit

2627

**SEARCHED**

Class	Subclass	Date	Examiner
369	44.16, 44.32, 53.19.	4/11/2006	VP

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
PGPUB	text search	4/11/2006	VP
Interference search (see search history printout)			

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East (PGPUB; USPAT; USOCR;EPO;JPO;DERWENT;IBM_T DB)  369 (text search only see search history printout).	4/11/2006	VP
Consulted Wayne Young	4/11/2006	VP